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## **Complete if Known**

Application Number	New Application 10/582,293
Filing Date	June 12, 2006
First Named Inventor	Matthew GAVED et al
Art Unit	2882
Examiner Name	Allen C. Ho
Attorney Docket Number	025538-00085

Sheet 1 of 2

## **NON PATENT LITERATURE DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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 Examiner  
Signature

/Allen C. Ho/

 Date  
Considered

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